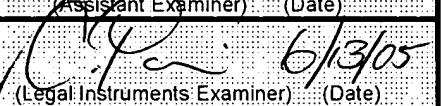


Issue Classification			Application/Control No.		Applicant(s)/Patent under Reexamination	
			10/660,078		RHEE, SHIN W.	
			Examiner		Art Unit	
			Jacob Y. Choi		2875	

ORIGINAL				CROSS REFERENCE(S)			
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
362	267	362	223	260	329		
INTERNATIONAL CLASSIFICATION							
F	2	1	V.	29/00	/	/	/
Jacob Y. Choi 06/01/2005 <small>(Assistant Examiner) (Date)</small>				 JOHN ANTHONY WARD 6/10/05 <small>(Primary Examiner) (Date)</small>			
 <small>(Legal Instruments Examiner) (Date)</small>				Total Claims Allowed: 8 O.G. Print Claim(s) 6 O.G. Print Fig. 18			

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R. 1.47	
Final	Original	Final	Original	Final	Original	Final	Original
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7	37	67	97	127	157	187	
8	38	68	98	128	158	188	
9	39	69	99	129	159	189	
10	40	70	100	130	160	190	
11	41	71	101	131	161	191	
12	42	72	102	132	162	192	
13	43	73	103	133	163	193	
14	44	74	104	134	164	194	
15	45	75	105	135	165	195	
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22	52	82	112	142	172	202	
23	53	83	113	143	173	203	
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26	56	86	116	146	176	206	
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29	59	89	119	149	179	209	
30	60	90	120	150	180	210	